## **Preliminary Constructions**

Goda Kaisha IP Bridge 1 v. Broadcom Ltd., et al., Case. No. 2:16-cv-134

U.S. Patents No. 6,538,324, 6,197,696, RE41,980, 7,126,174, 8,354,726, and RE43,729

Disputed Term	Preliminary Construction
United States	Patent No. 7,126,174
A. "a trench isolation region surrounding an active area of a semiconductor substrate" ('174 Pat., Cl. 1)	Plain and ordinary meaning (Reject Defendants' proposal of "lateral boundary)
United States	Patent No. 8,354,726
C. "formed on the side surface of the [first/second] gate electrode" ('726 Pat., Cls. 1, 43)	"covering the side surface of the [first/second] gate electrode"
D. "a stress-containing insulating film containing internal stress and formed to cover the first gate electrode, the first sidewall insulating film, the auxiliary pattern, and the second side-wall insulating film" ('726 Pat., Cl. 1)	"a stress-containing insulating film containing internal stress and also covering the first gate electrode, the first side-wall insulating film, the auxiliary pattern, and the second side-wall insulating film"
E. "the first gate electrode is formed on the first active region through a gate insulating film including nitrogen" ('726 Pat., Cls. 20, 43, 54)	"the first gate electrode is formed on the first active region, with a nitrogen-containing gate insulating film between the first gate electrode and the first active region"
F. "an interlayer insulating film on the silicide layer through the stress-containing insulating film" ('726 Pat., Cls. 23, 57)	"an interlayer insulating film formed on the silicide layer, with the stress-containing insulating film being between the interlayer insulating film and the silicide layer"

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United States Patent No. 6,197,696		
G. "using the [first resist pattern/second resist pattern and the mask pattern/patterned third insulating film] as a mask"	"using the [first resist pattern/second resist pattern and the mask pattern/patterned third insulating film] to define areas for etching"	
('696 Pat., Cl. 13)		
United States	Patent No. 6,538,324	
H. Preambles of Claims 1 and 5 of the '324 Patent	The phrase "[a] barrier film preventing diffusion of copper from a copper wiring layer formed on a semiconductor substrate" in Claim 1 and the phrase "prevents diffusion of copper from a copper wiring layer formed on a semiconductor substrate" in Claim 5 are not limiting.	
I. "film"	Plain and ordinary meaning	
J. "said first film being composed of	"the first film is distinct from the second film, and	
crystalline metal containing nitrogen therein"	the first film consists essentially of a mixture of	
('324 Pat., Cls. 1, 5)	throughout"	
	(Reject Defendants' proposal of "closed-ended")	
K. "said second film being composed of amorphous metal nitride"	"the second film is distinct from the first film, and the second film consists essentially of amorphous	
('324 Pat., Cls. 1, 5)	metal nitride"	
	(Reject Defendants' proposal of "closed-ended")	
L. "[said barrier film being constituted of] common metal atomic species"	"the layers of the barrier film contain atoms of the same metal"	
('324 Pat., Cls. 1, 5)		
United States	 Patent No. RE41,980	
M. "a surface protecting film"	"a surface protecting film including distinct first	
('980 Pat., Cls. 18, 35)	and second dielectric films"	
N. "interlayer insulating film"	"an insulating film located between but not	
('980 Pat., Cls. 18, 33, 35, 50)	within layers"	

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O. "small dielectric constant" ('980 Pat., Cls. 18, 35)	"a dielectric constant less than that of silicon dioxide"
P. "said bonding pad in said opening and said second dielectric film of said surface protecting film completely cover said first dielectric film so as not to expose said first dielectric film"  ('980 Pat., Cl. 18)	"the bonding pad and the second dielectric film collectively cover the first dielectric film so that it is not exposed to above"
Q. "wherein said bonding pad covers said opening" ('980 Pat., Cl. 35)	Plain and ordinary meaning
United States	Patent No. RE43,729
R. "performed within one cycle" ('729 Pat., Cl. 21)	"performed within one clock cycle"